

### **Description**

The AP80N08D uses advanced trench technology to provide excellent R<sub>DS(ON)</sub>, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

#### **General Features**

V<sub>DS</sub> = 80V I<sub>D</sub> =80A

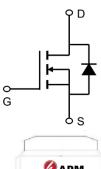
 $R_{DS(ON)}$  <  $6.5m\Omega$   $V_{GS}$ =10V

#### **Application**

Battery protection

Load switch

Uninterruptible power supply







#### **Package Marking and Ordering Information**

Product ID	Pack	Marking	Qty(PCS)
AP80N08D	TO-252-3L	AP80N08D XXX YYYY	2500

Absolute Maximum Ratings (T<sub>c</sub>=25°C unless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	80	V
VGS	Gate-Source Voltage	±20	V
I <sub>D</sub> @T <sub>C</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1,6</sup>	80	А
I <sub>D</sub> @T <sub>C</sub> =100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1,6</sup>	42.5	А
IDM	Pulsed Drain Current <sup>2</sup>	170	А
EAS	Single Pulse Avalanche Energy <sup>3</sup>	57.8	mJ
IAS	Avalanche Current	34	А
P <sub>D</sub> @T <sub>C</sub> =25°C	Total Power Dissipation <sup>4</sup>	56	W
TSTG	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
R <sub>θ</sub> JA	Thermal Resistance Junction-Ambient <sup>1</sup>	62	°C/W
R₀JC	Thermal Resistance Junction-Case <sup>1</sup>	2.2	°C/W



# Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	ol Parameter Conditions		Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	80			V
RDS(ON)	Static Drain-Source On-Resistance <sup>2</sup>	<sup>2</sup> V <sub>GS</sub> =10V , I <sub>D</sub> =20A		4.8	6.5	mΩ
RDS(ON)	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =4.5V , I <sub>D</sub> =20A		6.3	8.5	mΩ
V <sub>G</sub> S(th)	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	1.0		2.5	V
		V <sub>DS</sub> =64V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C	, V <sub>GS</sub> =0V , T <sub>J</sub> =25°C		1	
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =64V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C			5	uA
Igss	Gate-Source Leakage Current	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =5V , I <sub>D</sub> =20A		75		S
Rg	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		0.5		Ω
Qg	Total Gate Charge (10V)			40		
Qgs	Gate-Source Charge	VDS=40V , VGS=10V , ID=20A		7.2		nC
Qgd	Gate-Drain Charge	1		6.5		
Td(on)	Turn-On Delay Time			8.3		
Tr	Rise Time			4.2		
Td(off)	Turn-Off Delay Time	ID=20A		36		ns
Tf	Fall Time	1		6.9		
Ciss	Input Capacitance			2860		
Coss	Output Capacitance	─ VDS=40V , VGS=0V , f=1MHz		410		pF
Crss	Reverse Transfer Capacitance	1		38		
ls	Continuous Source Current <sup>1,5</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			48	Α
VsD	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =A , T <sub>J</sub> =25°C		0.77	1.0	V
trr	Reverse Recovery Time			27		nS
Qrr	Reverse Recovery Charge	lF=20A , dl/dt=100A/μs , T <sub>J</sub> =25°C		89		nC

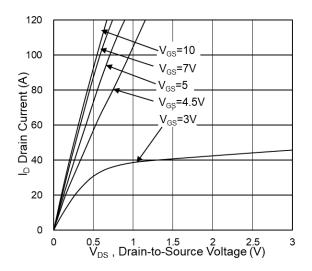
#### Note

- 1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width  $\,\leq\,300\text{us}$  , duty cycle  $\,\leq\,2\%$
- 3. The EAS data shows Max. rating . The test condition is  $V_{DD}$ =25V,  $V_{GS}$ =10V, L=0.1mH,  $I_{AS}$ =34A
- 4. The power dissipation is limited by 150°C junction temperature
- 5. The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.
- 6. The maximum current rating is package limited.



# **Typical Characteristics**

# 80V N-Channel Enhancement Mode MOSFET



**Fig.1 Typical Output Characteristics** 

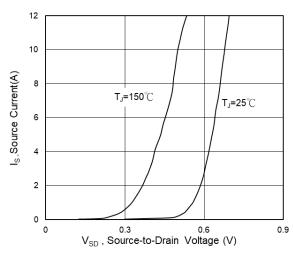


Fig.3 Source Drain Forward Characteristics

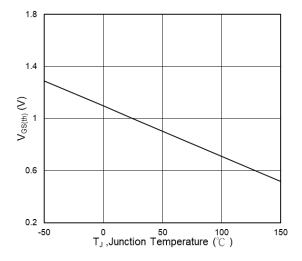


Fig.5 Normalized V<sub>GS(th)</sub> vs. T<sub>J</sub>

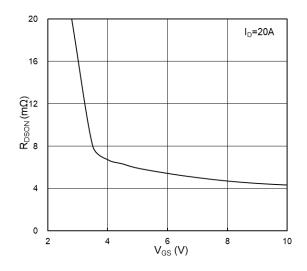


Fig.2 On-Resistance vs G-S Voltage

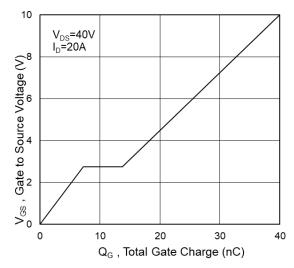


Fig.4 Gate-Charge Characteristics

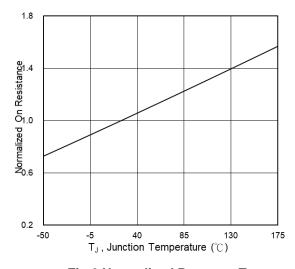
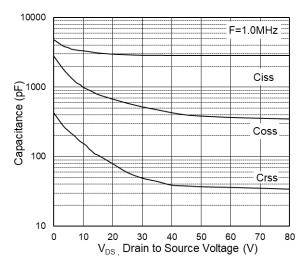


Fig.6 Normalized R<sub>DSON</sub> vs. T<sub>J</sub>







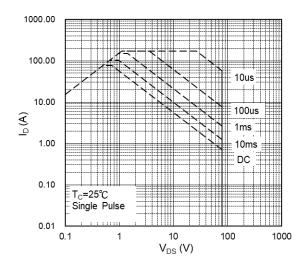


Fig.7 Capacitance

Fig.8 Safe Operating Area

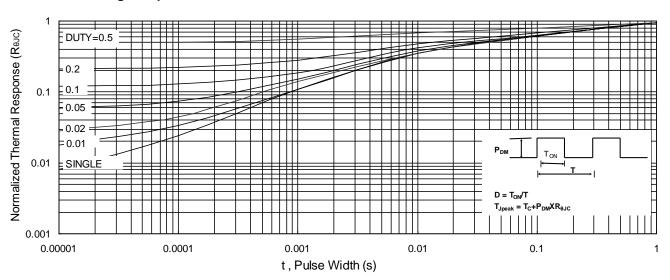


Fig.9 Normalized Maximum Transient Thermal Impedance

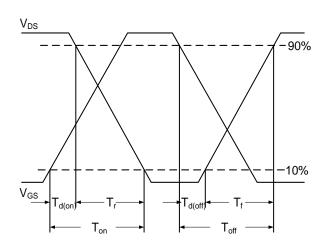


Fig.10 Switching Time Waveform

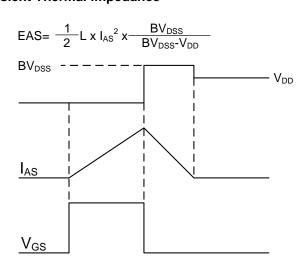
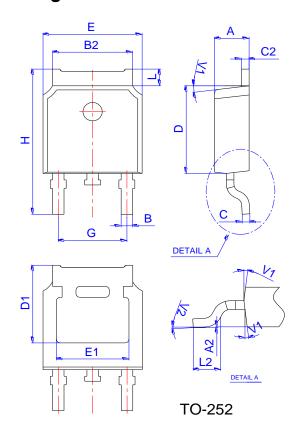


Fig.11 Unclamped Inductive Switching Waveform

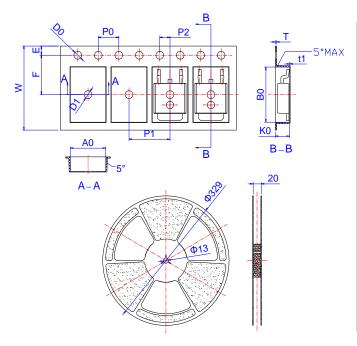


# Package Mechanical Data: TO-252-3L



	Dimensions					
Ref.	Millimeters			Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
Α	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
В	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
С	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
Е	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
Н	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

# **Reel Spectification**



	Dimensions					
Ref.	Millimeters			Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
Е	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
В0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
Т	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583



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